

PCN Number:	20230130003.1		PCN Date:	February 01, 2023	
Title:	Qualification of additional Fab sites (CFAB & DL-LIN) using qualified Process Technology and additional Assembly sites options for select devices				
Customer Contact:	PCN Manager		Dept:	Quality Services	
Proposed 1st Ship Date:	May 1, 2023		Sample requests accepted until:	Mar 3, 2023*	
*Sample requests received after Mar 3, 2023 will not be supported.					
Change Type:					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input checked="" type="checkbox"/>	Wafer Fab Site	<input checked="" type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process
		<input type="checkbox"/>	Part number change		
PCN Details					
Description of Change:					
Qualification of additional Fab sites (CFAB & DL-LIN) using qualified Process Technology and additional Assembly sites options for the list of devices in the product affected section below.					
Current Fab Site			Additional Fab Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
DL-LIN	LBC3S	150mm	CFAB DL-LIN	LBC3S	200mm
All devices listed below are currently in one or two of the following 3 Assembly sites: TI Malaysia, TI Taiwan, or TI Mexico. After expiration of this PCN, all devices can be built from any of these 3 assembly sites. BOM Materials are the same between all three sites.					
Qual details are provided in the Qual Data Section.					
Reason for Change:					
These changes are part of our multiyear plan to transition products from our 150- millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None					
Impact on Environmental Ratings					
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.					
RoHS		REACH		Green Status	
<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change
Changes to product identification resulting from this PCN:					

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DL-LIN	DLN	USA	Dallas
CFAB	CU3	CHN	Chengdu
DL-LIN	DLN	USA	Dallas

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
TI Mexico	MEX	MEX	Aguascalientes
TI Malaysia	MLA	MYS	KUALA LUMPUR
TI Taiwan	TAI	TWN	Chung Ho, New Taipei City

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS
 MADE IN: Malaysia
 2DC: 20:
 MSL 2 /260C/1 YEAR SEAL DT
 MSL 1 /235C/UNLIM 03/29/04
 OPT:
 ITEM: 39
LBL: 5A (L)T0:1750

(1P) SN74LS07NSR
 (Q) 2000 (D) 0336
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: 0000017
 (20L) CSO: SHE (21L) CCO:USA
 (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

Group 1 Device list (CFAB as additional Fab site & TI Mexico, Malaysia, & Taiwan Assembly sites)

TCA4311ADR	TLC2254IDR	TLC2274ACDR	TLV2264AID
TLC084AID	TLC2264AID	TLC2274AID	TLV2264AIDR
TLC084AIDR	TLC2264AIDR	TLC2274AIDR	TLV2264ID
TLC084CD	TLC2264CD	TLC2274CD	TLV2264IDR
TLC084CDR	TLC2264CDR	TLC2274CDR	TLV2371ID
TLC084ID	TLC2264ID	TLC2274ID	TLV2371IDR
TLC084IDR	TLC2264IDR	TLC2274IDR	TLV2374ID
TLC2252AID	TLC2272ACD	TLV2252AID	TLV2374IDR
TLC2252AIDR	TLC2272ACDR	TLV2252AIDR	TLV271CDR
TLC2252CD	TLC2272AID	TLV2252ID	TLV271ID
TLC2252CDR	TLC2272AIDR	TLV2252IDR	TLV271IDR
TLC2252IDR	TLC2272CD	TLV2254AID	TLV274CD
TLC2254AID	TLC2272CDR	TLV2254AIDR	TLV274CDR
TLC2254AIDR	TLC2272ID	TLV2254ID	TLV274ID
TLC2254CDR	TLC2272IDR	TLV2254IDR	TLV274IDR
TLC2254ID	TLC2274ACD		

Group 2 Device list (CFAB & DFAB8 as additional Fab sites & TI Mexico, Malaysia, & Taiwan Assembly sites)

TLC072AID	TLC082AID	TLV2462AIDR	TLV2474ID
TLC072AIDR	TLC082AIDR	TLV2462CD	TLV2474IDR
TLC072CD	TLC082CD	TLV2462CDR	TLV272CDR
TLC072CDR	TLC082CDR	TLV2462ID	TLV272ID
TLC072ID	TLC082ID	TLV2462IDR	TLV272IDR
TLC072IDR	TLC082IDR	TLV2463AIDR	TPS3705-30D
TLC074AID	TLC083CDR	TLV2463CDR	TPS3705-30DR
TLC074AIDR	TLV2370IDR	TLV2463ID	TPS3705-33D
TLC074CD	TLV2372ID	TLV2474AID	TPS3705-33DR
TLC074CDR	TLV2372IDR	TLV2474AIDR	TPS3705-50D
TLC074ID	TLV2373IDR	TLV2474CD	TPS3705-50DR
TLC074IDR	TLV2462AID	TLV2474CDR	

For alternate parts with similar or improved performance, please visit the product page on TI.com



**TI Information
Selective Disclosure**

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLV2401QDBVRQ1	QBS Process Reference: MAX3243IPWG4DL
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/231/0
HTSL	High Temp Storage Bake 175C	500 Hours	3/135/0	-
HTOL	Life Test, 150C	408 Hours	3/231/0	3/231/0
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0
HBM	ESD - HBM - Q100	500 V	1/3/0	-
CDM	ESD - CDM - Q100	1500 V	1/3/0	-
LU	Latch-up	(per JESD78)	1/6/0	-
ED	Electrical Characterization	Per Datasheet parameters	3/90/0	-

- QBS: Qual By Similarity
 - Qual Device TLV2401QDBVRQ1 is qualified at LEVEL1-260C
A1 (PC): Preconditioning:
 Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:
 Grade 0 (or E): -40°C to +150°C
 Grade 1 (or Q): -40°C to +125°C
 Grade 2 (or T): -40°C to +105°C
 Grade 3 (or L): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):
 Room/Hot/Cold: HTOL, ED
 Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU
 Room: AC/uHAST

Green/Pb-free Status:
 Qualified Pb-Free(SMT) and Green
 TI Qualification ID: 20190124-128331



TI Information
 Selective Disclosure

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLC2264AQPWRQ1	Qual Device: TLC2264AIDRCT	QBS Process Reference: CD3301RHHR	QBS Package Reference: TLV9064QPWRQ1
HTOL	Life Test, 150C	300 Hours	1/3/0	-	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	3/231/0	1/45/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-
AC	Autoclave 121C	96 Hours	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2000 V	1/3/0	-	1/3/0	-
CDM	ESD - CDM	750 V	1/3/0	-	1/3/0	-
LU	Latch-up	(per JESD78)	1/6/0	-	1/6/0	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	-	1/30/0	-
MQ	Assembly MQ	Per Site Specifications	Pass	Pass	Pass	Pass

- QBS: Qual By Similarity
 - Qual Device TLC2264AQPWRQ1 is qualified at LEVEL1-260C
 - Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 - The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
 Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:
 Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20200903-135990



TI Information
 Selective Disclosure

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLV2464CPWR	QBS Process Reference: CD3301RHHR	QBS Package Reference: TPS2042BD	QBS Package Reference: TPS2419DR
HTOL	Life Test, 150C	300 Hours	-	3/231/0	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	3/231/0	3/231/0	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-	3/231/0
AC	Autoclave 121C	96 Hours	-	3/231/0	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	1/3/0	-	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-	-
LU	Latch-up	(per JESD78)	1/6/0	1/6/0	-	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	-	-
MQ	Assembly MQ	Per Site Specifications	Pass	Pass	Pass	Pass

- QBS: Qual By Similarity
 - Qual Device TLV2464CPWR is qualified at LEVEL1-260C
 - Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 - The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
 Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:
 Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20210308-139022

Qualification Report

Product Attributes

Attributes	Qual Device: 1P8T245NSR	Qual Device: ADS900E	Qual Device: PCM1801U	Qual Device: SN65HVD1781DR	Qual Device: TCA9546ADR	Qual Device: TCA9546ADR_RLF	Qual Device: TL494IDR
Assembly Site	MLA	MLA	MLA	MLA	MLA	MLA	FMX
Package Family	SOP	SSOP	SOIC	SOIC	SOIC	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V0
Wafer Fab Supplier	FFAB	TSMC WF2	TSMC WF2	DM5	MH8	MH8	SFAB
Wafer Fab Process	ASL3C	0.6-DPDM	0.6-DPDM	LBC5X	LBC7	LBC7	J11

Product Attributes

Attributes	Qual Device: TLC320AD77CDBR	Qual Device: TPS2074DB	Qual Device: TPS2101D	Qual Device: TPS2214ADB	Qual Device: TSS721AD	Qual Device: UC27131D	QBS Package Reference: ULQ2003AQDRQ1_STDLF
Assembly Site	MLA	MLA	TAI	MLA	TAI	FMX	FMX
Package Family	SSOP	SSOP	SOIC	SSOP	SOIC	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	ANAM-1, DFAB	DFAB	DFAB	DFAB	SFAB	SFAB	SFAB
Wafer Fab Process	33A21X3, 33C10X3	LBC3S	LBC3S	LBC3S	J11	J1-PWR1	J11-SLM

- QBS: Qual By Similarity

- Qual Devices qualified at LEVEL1-260C: TL494IDR, TSS721AD, 1P8T245NSR, PCM1801U, TLC320AD77CDBR, TPS2074DB, TPS2101D, SN65HVD1781DR, TCA9546ADR, TPS2214ADB

- Qual Devices qualified at LEVEL2-260C: ADS900E, UC27131D

- Device TLC320AD77CDBR contains multiple dies.

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: 1P8T245NSR	Qual Device: ADS900E	Qual Device: PCM1801U	Qual Device: SN65HVD1781DR	Qual Device: TCA9546ADR	Qual Device: TCA9546ADR_RLF	Qual Device: TL494IDR
AC	Autoclave 121C	96 Hours	3/231/0	-	3/231/0	-	3/231/0	3/231/0	-
FLAM	Flammability (UL 94V-0)	-	-	-	-	-	3/15/0	3/15/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	3/231/0	-	3/231/0	3/231/0	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	-
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/222/0	3/231/0	3/231/0	3/231/0	3/231/0	-
TC-BP	Post TC Bond Pull	Wires	-	-	-	3/90/0	3/162/0	3/90/0	-

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLC320AD77CDBR	Qual Device: TPS2074DB	Qual Device: TPS2101D	Qual Device: TPS2214ADB	Qual Device: TSS721AD	Qual Device: UC27131D	QBS Package Reference: ULQ2003AQDRQ1_STDLF
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	-	3/231/0	-	-	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0
HTOL	Life Test, 150C	408 Hours	-	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	-	1/45/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	-	3/231/0	-	-	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	-
MQ	Manufacturability (Auto Assembly)	(per automotive requirements)	-	-	-	-	-	-	Pass
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	-	3/231/0
TC-BP	Post TC Bond Pull	Wires	-	-	-	-	-	-	1/30/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20141019-109101, 20140520-104903 (QBS)

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN_ww_admin_team@list.ti.com

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